

DIGITRON SEMICONDUCTORS

MFE211 – MFE212

N-CHANNEL DUAL GATE SILICON NITRIDE
PASSIVATED MOS FIELD EFFECT TRANSISTORS

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain Source Voltage	V_{DSX}	20	Vdc
Drain Gate Voltage	V_{DG1}	35	Vdc
	V_{DG2}	35	
Gate Current	I_{G1}	±10	mAdc
	I_{G2}	±10	
Drain Current – Continuous	I_D	50	mAdc
Total Power Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D	360	mW
		2.4	mW/°C
Total Power Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	1.2	Watt
		8.0	mW/°C
Storage Channel Temperature Range	T_{stg}	-65 to +200	°C
Junction Temperature Range	T_J	-65 to +175	°C
Lead Temperature, 1/16" from Seated Surface for 10 Seconds	T_L	300	°C

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristics	Symbol	Min	Max	Unit	
OFF CHARACTERISTICS					
Drain Source Breakdown Voltage ($I_D = 10 \mu\text{Adc}$, $V_{G1S} = V_{G2S} = -4.0 \text{ Vdc}$)	$V_{(BR)DSX}$	20	-	Vdc	
Gate 1 – Source Breakdown Voltage ⁽¹⁾ ($I_{G1} = \pm 10 \text{ mAdc}$, $V_{G2S} = V_{DS} = 0$)	$V_{(BR)G1SO}$	±6.0	-	Vdc	
Gate 2 – Source Breakdown Voltage ⁽¹⁾ ($I_{G2} = \pm 10 \text{ mAdc}$, $V_{G1S} = V_{DS} = 0$)	$V_{(BR)G2SO}$	±6.0	-	Vdc	
Gate 1 to Source Cutoff Voltage ($V_{DS} = 15 \text{ Vdc}$, $V_{G2S} = 4.0 \text{ Vdc}$, $I_D = 20 \mu\text{Adc}$)	MFE211 $V_{G1S(off)}$	-0.5	-5.5	Vdc	
Gate 2 to Source Cutoff Voltage ($V_{DS} = 15 \text{ Vdc}$, $V_{G1S} = 0$, $I_D = 20 \mu\text{Adc}$)	MFE211 $V_{G2S(off)}$	-0.2	-2.5	Vdc	
Gate 1 Leakage Current ($V_{G1S} = \pm 5.0 \text{ Vdc}$, $V_{G2S} = V_{DS} = 0$) ($V_{G1S} = -5.0 \text{ Vdc}$, $V_{G2S} = V_{DS} = 0$, $T_A = 150^\circ\text{C}$)	I_{G1SS}	-	±10	mAdc	
		-	-10	μAdc	
Gate 2 Leakage Current ($V_{G2S} = \pm 5.0 \text{ Vdc}$, $V_{G1S} = V_{DS} = 0$) ($V_{G2S} = -5.0 \text{ Vdc}$, $V_{G1S} = V_{DS} = 0$, $T_A = 150^\circ\text{C}$)	I_{G2SS}	-	±10	nAdc	
		-	-10	μAdc	
ON CHARACTERISTICS					
Zero-Gate Voltage Drain Current ⁽²⁾ ($V_{DS} = 15 \text{ Vdc}$, $V_{G1S} = 0$, $V_{G2S} = 4.0 \text{ Vdc}$)	I_{DSS}	6.0	40	mAdc	
SMALL SIGNAL CHARACTERISTICS					
Forward Transfer Admittance ⁽³⁾ ($V_{DS} = 15 \text{ Vdc}$, $V_{G2S} = 4.0 \text{ Vdc}$, $V_{G1S} = 0$, $f = 1.0 \text{ kHz}$)	$ Y_{fs} $	17	40	mmhos	
Reverse Transfer Capacitance ($V_{DS} = 15 \text{ Vdc}$, $V_{G2S} = 4.0 \text{ Vdc}$, $I_D = 10 \text{ mAdc}$, $f = 1.0 \text{ MHz}$)	C_{rss}	0.005	0.05	pF	
FUNCTIONAL CHARACTERISTICS					
Noise Figure ($V_{DD} = 18 \text{ Vdc}$, $V_{GG} = 7.0 \text{ Vdc}$, $f = 200 \text{ MHz}$) ($V_{DD} = 24 \text{ Vdc}$, $V_{GG} = 6.0 \text{ Vdc}$, $f = 45 \text{ MHz}$)	MFE211	NF	-	3.5	dB
	MFE212		-	4.0	
Common Source Power Gain ($V_{DD} = 18 \text{ Vdc}$, $V_{GG} = 7.0 \text{ Vdc}$, $f = 200 \text{ MHz}$) ($V_{DD} = 18 \text{ Vdc}$, $V_{GG} = 6.0 \text{ Vdc}$, $f = 45 \text{ MHz}$) ($V_{DD} = 18 \text{ Vdc}$, $f_{LO} = 245 \text{ MHz}$, $f_{RF} = 200 \text{ MHz}$)	MFE211	G_{ps}	24	35	dB
	MFE211	$G_c^{(5)}$	29	37	
	MFE212		21	28	

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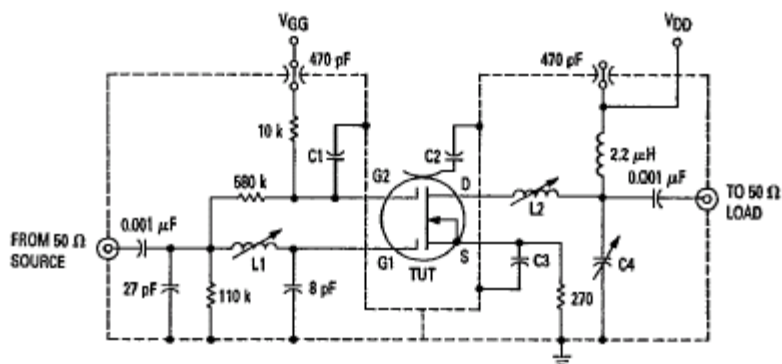
ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristics		Symbol	Min	Max	Unit
Bandwidth ($V_{DD} = 18\text{ Vdc}$, $V_{GG} = 7.0\text{ Vdc}$, $f = 200\text{ MHz}$) ($V_{DD} = 18\text{ Vdc}$, $f_{LO} = 245\text{ MHz}$, $f_{RF} = 200\text{ MHz}$) ($V_{DD} = 18\text{ Vdc}$, $V_{GG} = 6.0\text{ Vdc}$, $f = 45\text{ MHz}$)	MFE211	BW	5.0	12	MHz
	MFE212		4.0	7.0	
	MFE211		3.5	6.0	
Gain Control Gate Supply Voltage ⁽⁴⁾ ($V_{DD} = 18\text{ Vdc}$, $\Delta G_{ps} = -30\text{ dB}$, $f = 200\text{ MHz}$) ($V_{DD} = 18\text{ Vdc}$, $\Delta G_{ps} = -30\text{ dB}$, $f = 45\text{ MHz}$)	MFE211	$V_{GG(GC)}$	-	-2.0	Vdc
	MFE211		-	± 1.0	

1. All gate breakdown voltages are measured while the device is conducting rated gate current. This ensures that the gate voltage limiting network is functioning properly.
2. Pulse test: Pulse width = 300 μs , duty cycle $\leq 2\%$.
3. This parameter must be measured with bias voltages applied for less than 5 seconds to avoid overheating. The signal is applied to gate 1 with gate 2 at ac ground.
4. ΔG_{ps} is defined as the change in G_{ps} from the value at $V_{GG} = 7.0$ volts (MFE211).
5. Power Gain Conversion. Amplitude at input from local oscillator is adjusted for maximum G_c .

Available Non-RoHS (standard) or RoHS compliant (add PBF suffix).

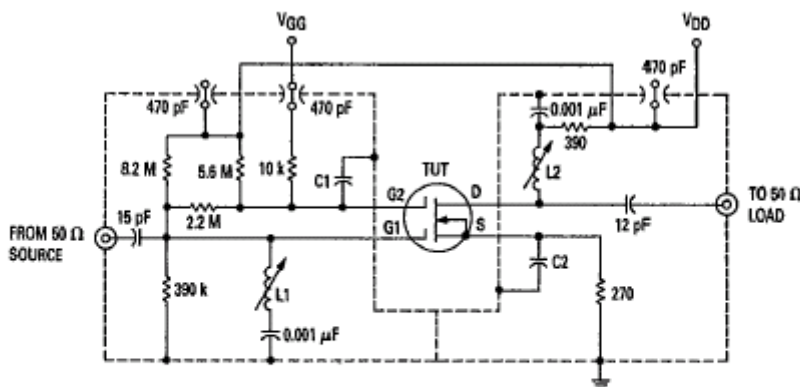
Available as "HR" (high reliability) screened per MIL-PRF-19500, JANTX level. Add "HR" suffix to base part number.



C1, C2 & C3: Leadless disc ceramic, 0.001 μF
C4: ARCO 462, 5–80 pF, or equivalent

L1: 3 Turns #18, 3/16" diameter aluminum slug
L2: 8 Turns #20, 3/16" diameter aluminum slug

Figure 1. 200 MHz Power Gain, Gain Control Voltage, and Noise Figure Test Circuit for MFE211



C1: Leadless disc ceramic, 0.001 μF
C2: Leadless disc ceramic, 0.01 μF

L1: 8 Turns #28, 5/32" diameter form, type "J" slug
L2: 9 Turns #28, 5/32" diameter form, type "J" slug

Figure 2. 45 MHz Power Gain and Noise Figure Test Circuit for MFE211

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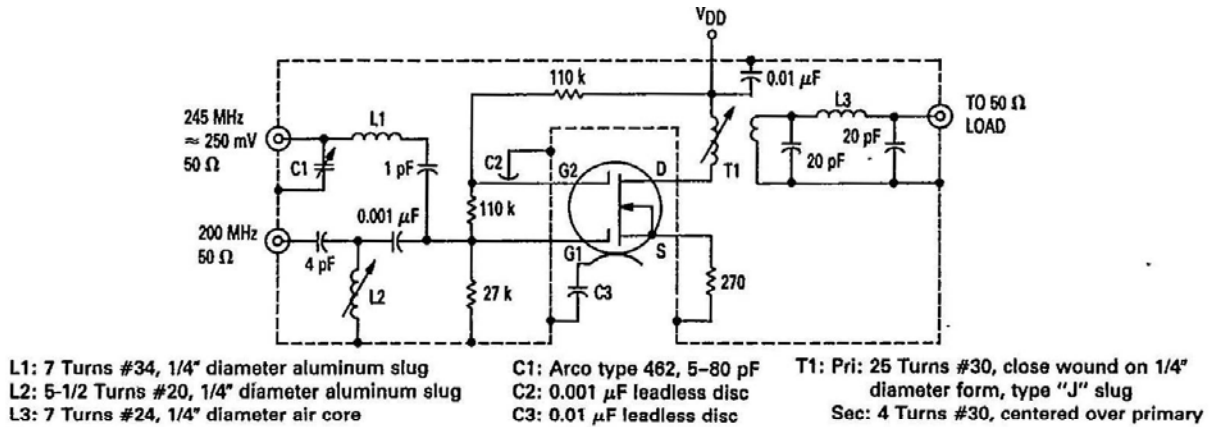


Figure 3. 200 MHz-to-45 MHz Circuit for Conversion Power Gain for MFE212

TYPICAL CHARACTERISTICS

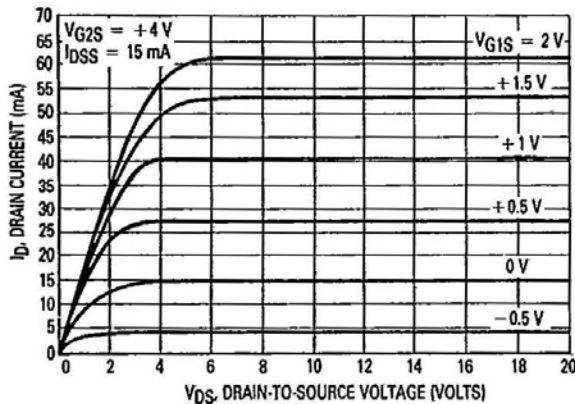


Figure 4. Drain Current versus Drain-to-Source Voltage

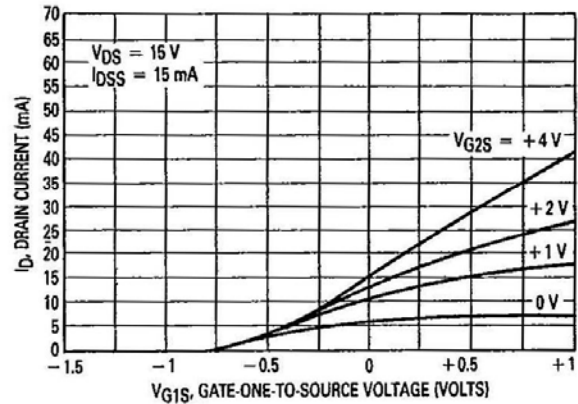


Figure 5. Drain Current versus Gate-One-to-Source Voltage

SMALL-SIGNAL COMMON-SOURCE PARAMETER

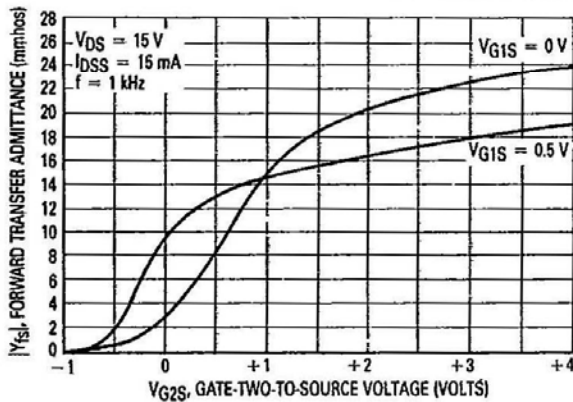


Figure 6. Forward Transfer Admittance versus Gate-Two-to-Source Voltage

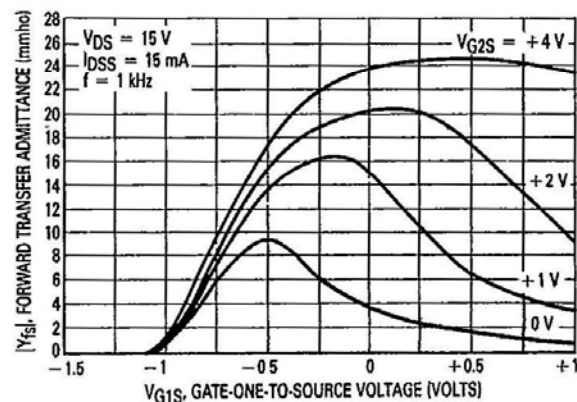


Figure 7. Forward Transfer Admittance versus Gate-One-to-Source Voltage

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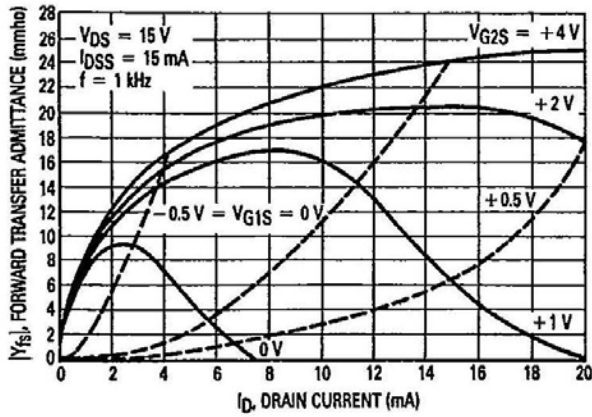


Figure 8. Forward Transfer Admittance versus Drain Current

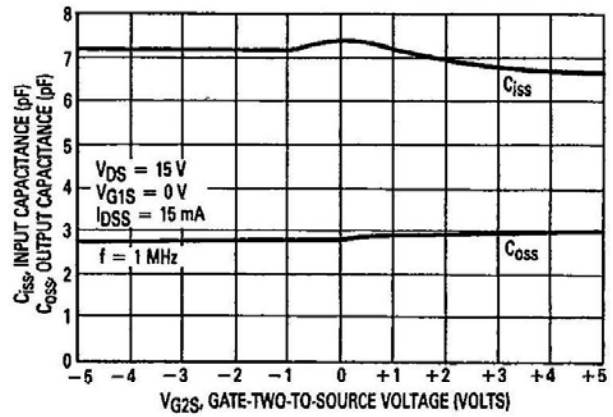


Figure 9. Input and Output Capacitance versus Gate-Two-to-Source Voltage

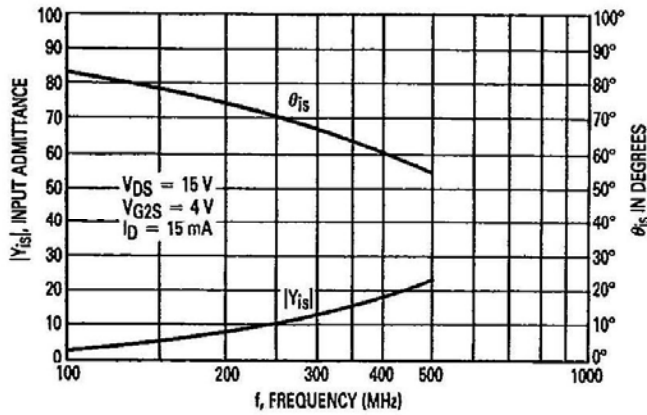


Figure 10. Small-Signal Gate-One Input Admittance versus Frequency

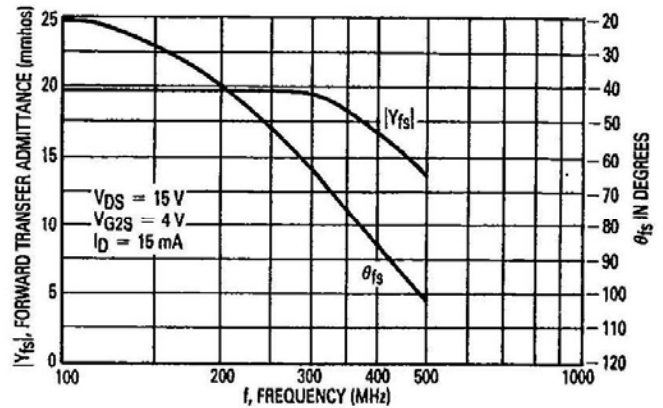


Figure 11. Small-Signal Forward Transfer Admittance versus Frequency

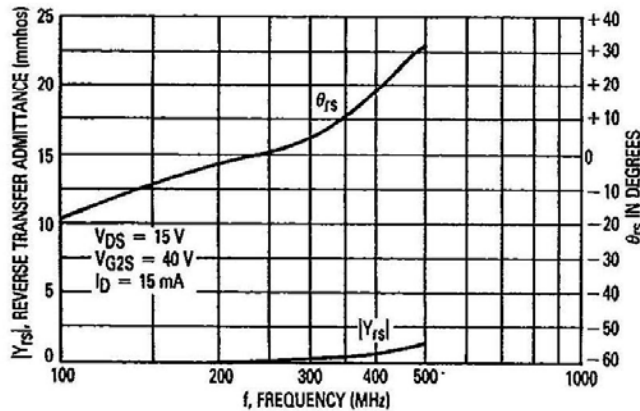


Figure 12. Small-Signal Gate-One Reverse Transfer Admittance versus Frequency

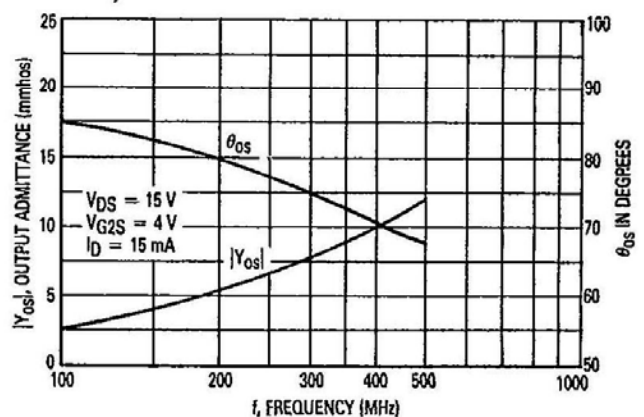


Figure 13. Small-Signal Gate-One Output Admittance versus Frequency

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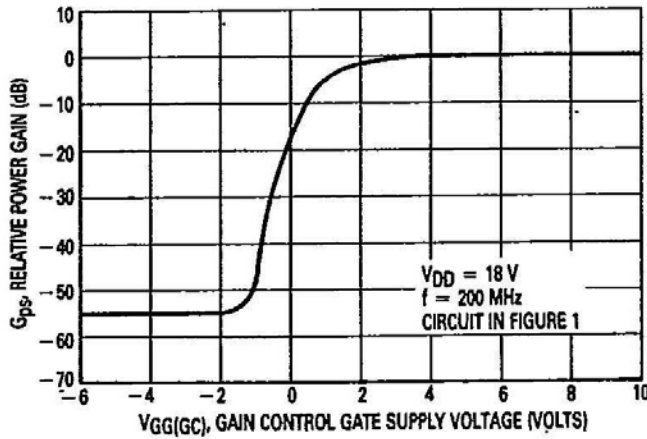


Figure 14. Relative Small-Signal Power Gain versus Gain Control Gate Supply Voltage
MFE211

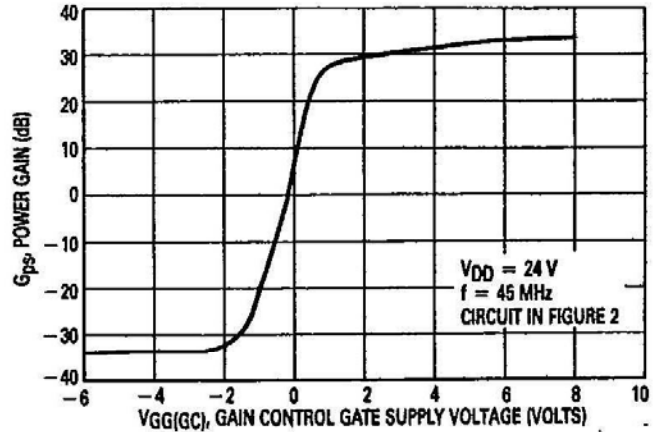


Figure 15. Small-Signal Common-Source Insertion Power Gain versus Gain Control Gate Supply Voltage

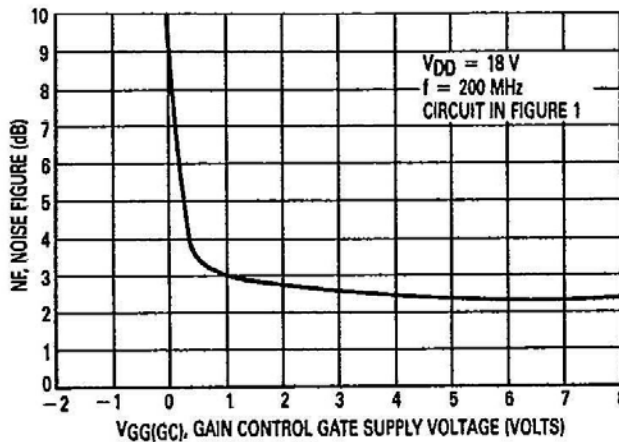


Figure 16. Common Source Spot Noise Figure versus Gain Control Gate Supply Voltage

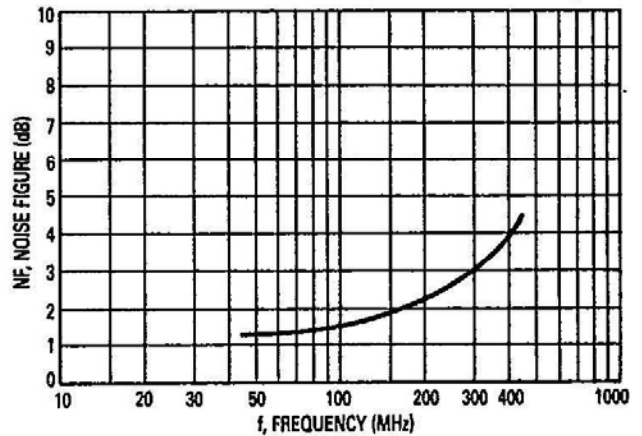
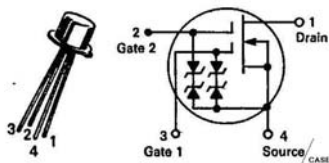


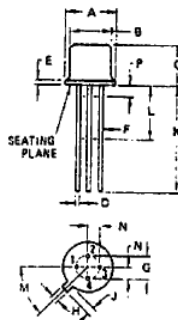
Figure 17. Optimum Spot Noise Figure versus Frequency

TO-72



DUAL-GATE
MOSFETs

N-CHANNEL — DEPLETION



Dim	Inches		Millimeters	
	Min	Max	Min	Max
A	-	0.230	-	5.840
B	-	0.195	-	4.950
C	-	0.210	-	5.330
D	-	0.021	-	0.530
E	-	0.030	-	0.760
F	-	0.019	-	0.480
G	0.100 BSC	-	2.540 BSC	-
H	-	0.046	-	1.170
J	-	0.0480	-	1.220
K	0.500	-	12.700	-
L	0.250	-	6.350	-
M	45°C BSC	-	45°C BSC	-
N	0.050 BSC	-	1.270 BSC	-
P	-	0.050	-	1.270